## Issue Classification



Application/Control No.

10/554,025

Reexamination
MITSUTANI, NORITAKE

Applicant(s)/Patent under

Art Unit

3747

Print Claim(s)

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Print Fig.

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Examiner Erick R. Solis

**ISSUE CLASSIFICATION** ORIGINAL INTERNATIONAL CLASSIFICATION CLASS SUBCLASS CLAIMED NON-CLAIMED 123 674 1 1 **CROSS REFERENCES** CLASS SUBCLASS (ONE SUBCLASS PER BLOCK) 701 103 109 1 ./ 1 1 1 1 1 **Total Claims Allowed: 11 Erick Solis** (Assistant Examiner) (Date) Art Unit 3747 O.G. O.G.

(Primary Examiner)

(Date)

Claims renumbered in the same order as presented by applicant												Пс	□ CPA □ T.D. □ R						1 47
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(Legal Instruments Examiner)